

VMDSEMI

VFTP010R050NA

Datasheet

General Description

The VMD VFTD010R050NB MOSFET is based on unique device design to achieve low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. The high V_{th} series is specially optimized for high systems with gate driving voltage greater than 10V.

Symbol

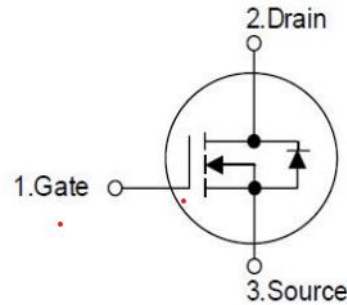


Figure 1 Symbol of VFTP010R050NA

Features

- Ultra Low $R_{DS(ON)_{max}} = 5.0m\Omega @ V_{GS} = 10V$.
- Extremely low switching loss
- Excellent stability and uniformity
- 100% UIS tested , 100% ΔV_{DS} Tested
- RoHS and Halogen-Free Compliant

Package Type

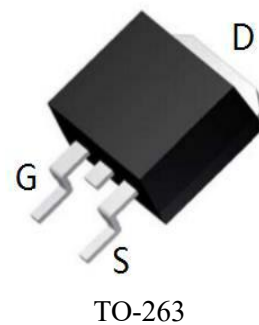


Figure 2 Package Type of VFTP010R050NA

Application

- Charger / Adapter
- Server/Telecom
- Synchronous Rectification
- High Frequency Switching

Ordering Information

Product Name	Package
VFTP010R050NA	TO-263

Absolute Maximum Ratings

Parameter		Symbol	Rating	Unit
Drain-Source Voltage		V_{DSS}	100	V
Gate-Source Voltage		V_{GSS}	±20	V
Continuous Drain Current	$T_C=25^{\circ}\text{C}$ (Note 5)	I_D	145	A
	$T_C=100^{\circ}\text{C}$ (Note 5)		91	
Pulsed Drain Current (Note 3)		I_{DM}	580	A
Power Dissipation, $T_C=25^{\circ}\text{C}$ (Note 2)		P_D	167	W
Avalanche Energy, Single Pulse (Note 3,Note6)		E_{AS}	136	mJ
Avalanche Current, Repetitive (Note 3,Note6)		I_{AS}	23	A
Operating and Storage Temperature Range		T_J	-55 to 150	°C

Thermal Resistance

Parameter	Symbol	Min	Typ	Max	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$			0.75	°C/W
Thermal Resistance, Junction-to-Ambient (Note 1,Note4)	$R_{\theta JA}$			55	°C/W

Notes:

1. The value of $R_{\theta JC}$ is measured in a still air environment with $T_A = 25^{\circ}\text{C}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
2. The power dissipation P_D is based on $T_{J(MAX)}=150^{\circ}\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heat sinking is used.
3. Single pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$.
4. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
5. The maximum current rating is package limited.
6. The EAS data shows Max. rating. The test condition is $V_{DS}=50\text{V}, V_{GS}=10\text{V}, L=0.5\text{mH}$

Thermal Resistance $T_J=25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Statistic Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	100			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=80V, V_{GS}=0V$			1	μA
Gate-Body Leakage Current	Forward	$I_{GSSF}, V_{GS}=20V, V_{DS}=0V$			100	nA
	Reverse	$I_{GSSR}, V_{GS}=-20V, V_{DS}=0V$			-100	
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	3.0	4.0	V
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=20A$		4.2	5.0	mΩ
Gate Resistance	R_G	f=1MHz, Open Drain		1.75		Ω
Dynamic Characteristics						
Input Capacitance	C_{ISS}	$V_{DS}=50, V_{GS}=0V,$ f=1MHz		3610		pF
Output Capacitance	C_{OSS}			1240		pF
Reverse Transfer Capacitance	C_{RSS}			32		pF
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=50V, I_D=50A,$ $R_G=3.0\Omega, V_{GS}=10V$		28		ns
Rise Time	t_r			24		
Turn-off Delay Time	$t_{d(off)}$			64		
Fall Time	t_f			22		
Gate Charge Characteristics						
Gate to Source Charge	Q_{gs}	$V_{DD}=50V, I_D=50A,$ $V_{GS}=10V$		16		nC
Gate to Drain Charge	Q_{gd}			20		
Gate Charge Total	Q_g			65.5		
Reverse Diode Characteristics						
Continuous Source Current	I_S				145	A
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_{SD}=20A$		0.8	1.0	V
Reverse Recovery Time	t_{rr}	$I_{SD}=20A,$		63		ns
Reverse Recovery Charge	Q_{rr}	dI _F /dt=100A/us		95		nC

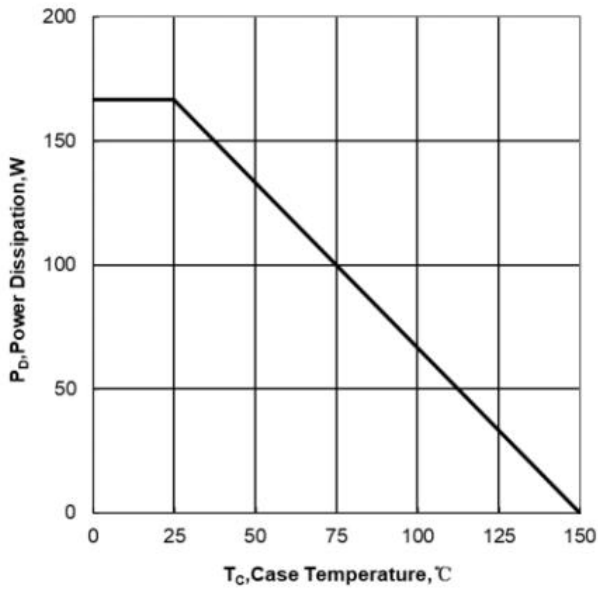
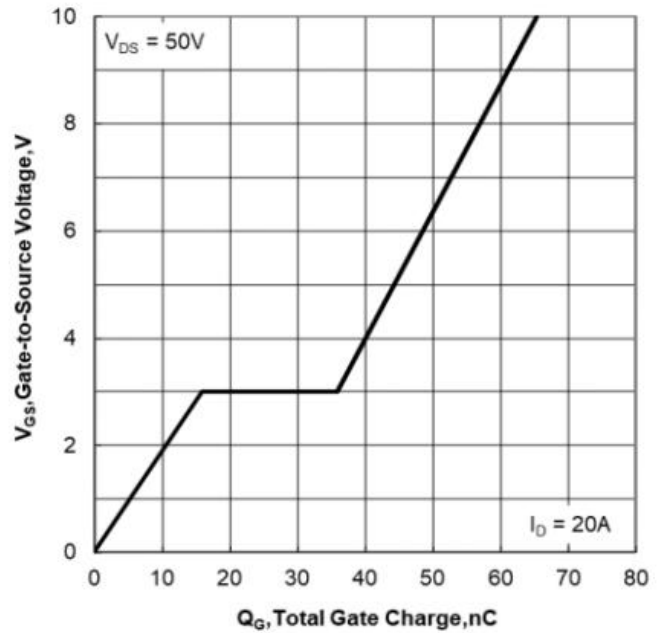
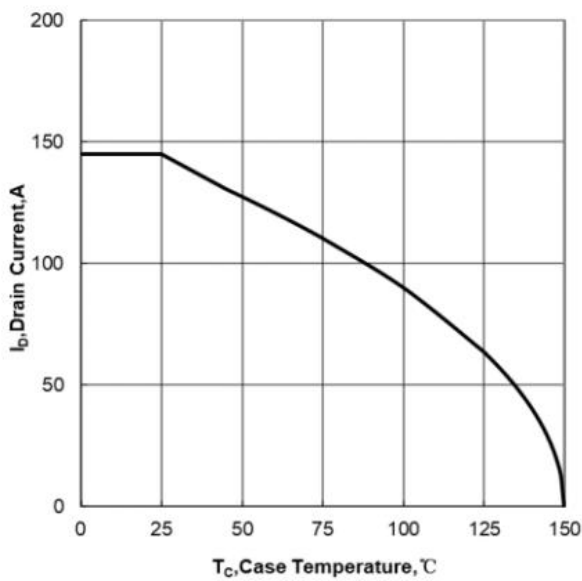
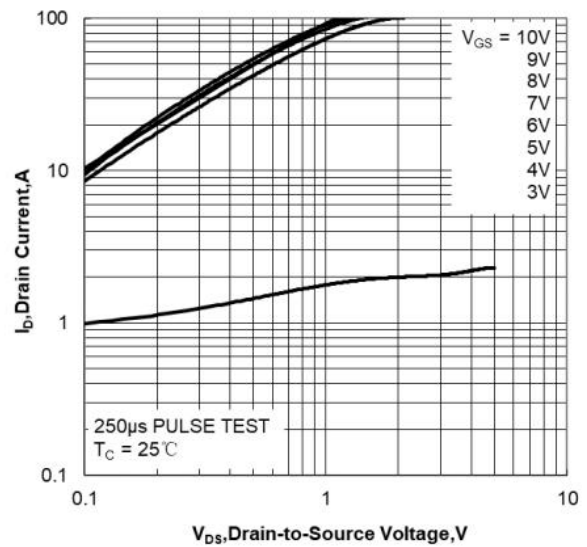
Typical Performance Characteristics
Figure 3: Maximum Power Dissipation vs Case Temperature

Figure 4: Gate Charge

Figure 5: Maximum Continuous Drain Current vs Case Temperature

Figure 6: Output Characteristics


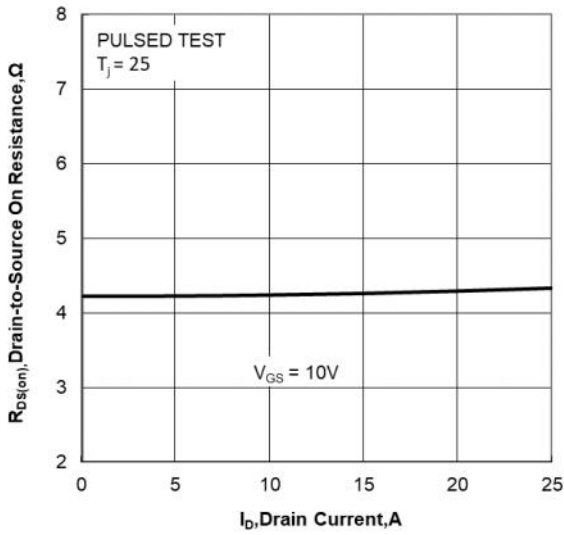
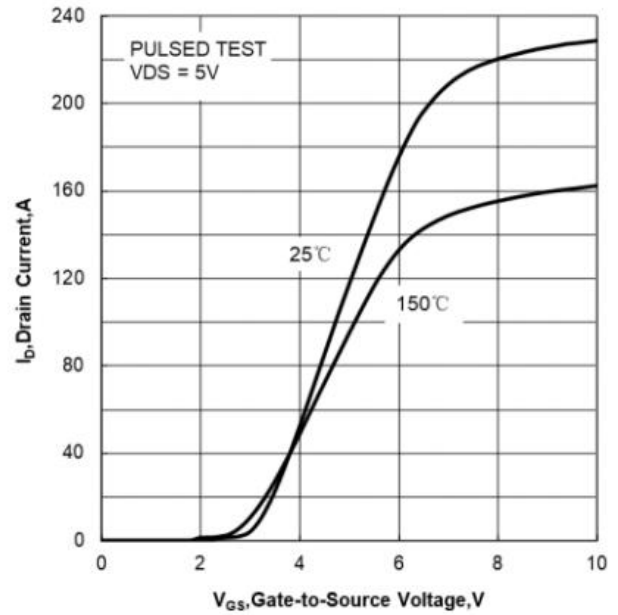
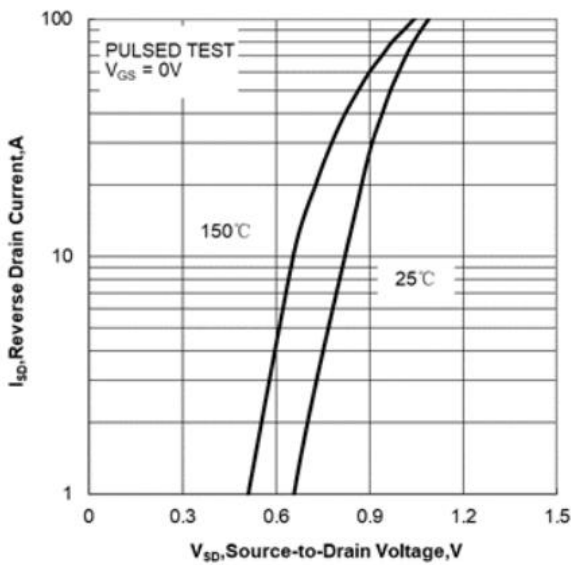
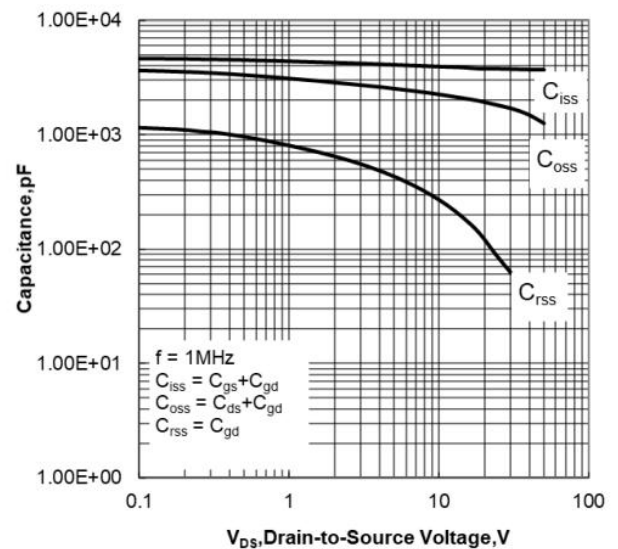
Figure 7: Drain-to-Source On Resistance vs Drain Current

Figure 8: Transfer Characteristics

Figure 9: Body Diode Forward Voltage vs Source Current and Temperature

Figure 10: Capacitance Characteristics


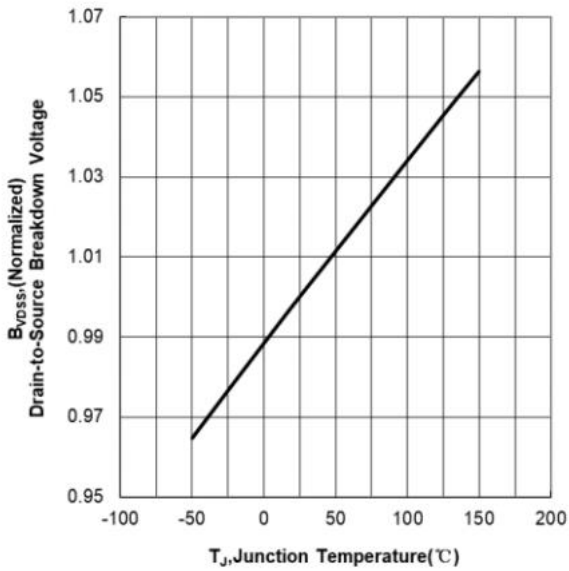
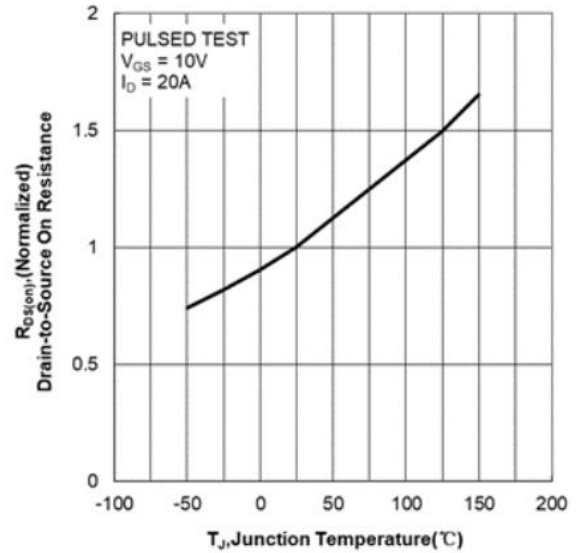
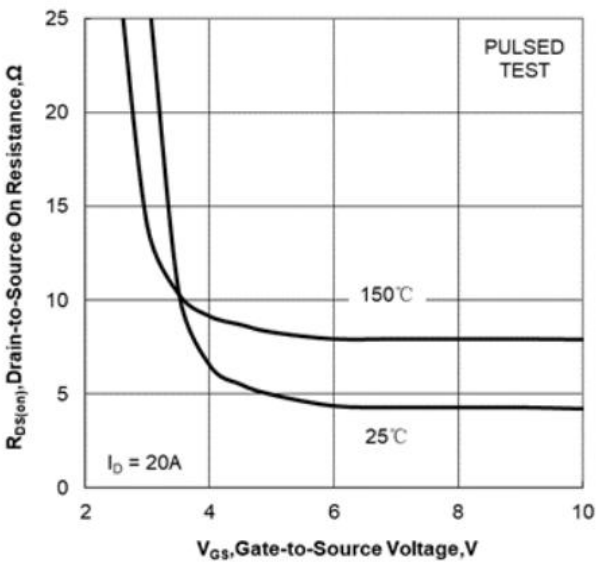
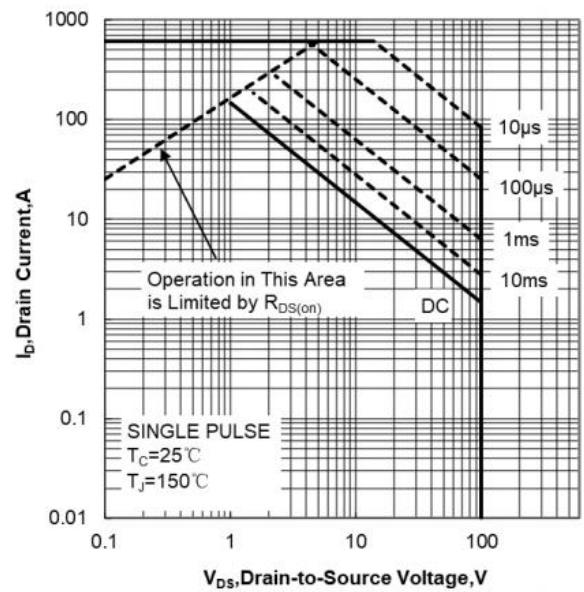
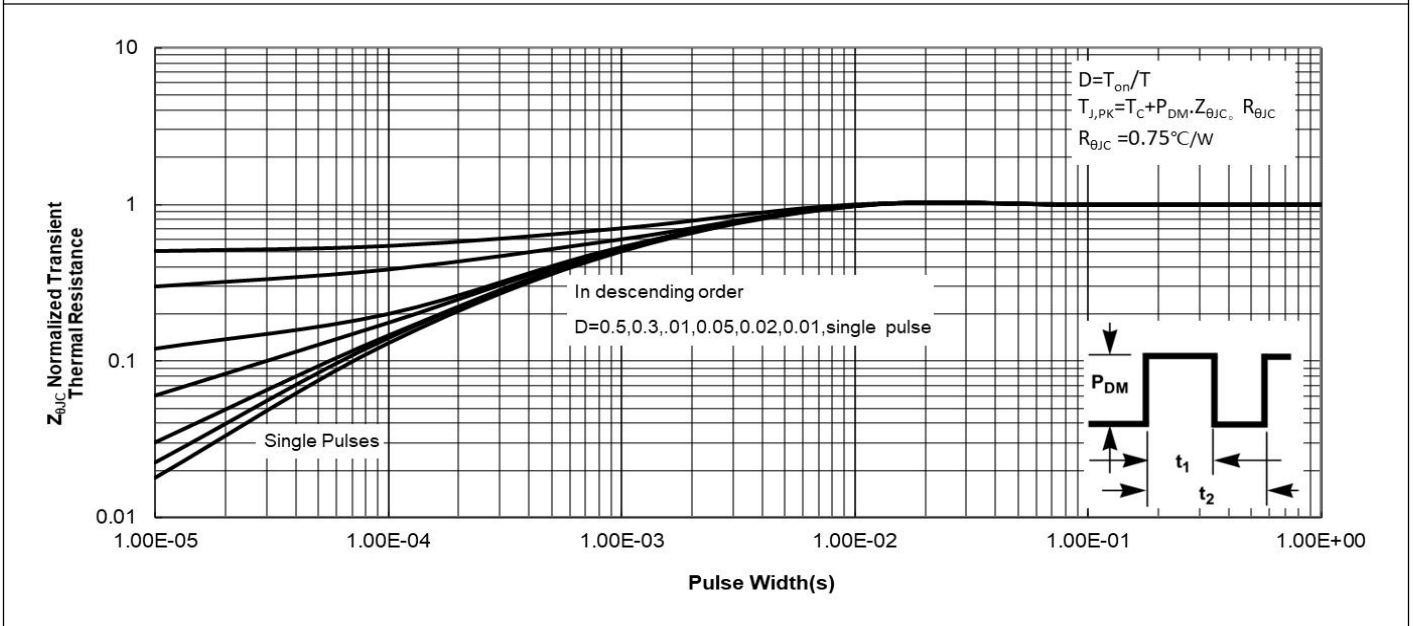
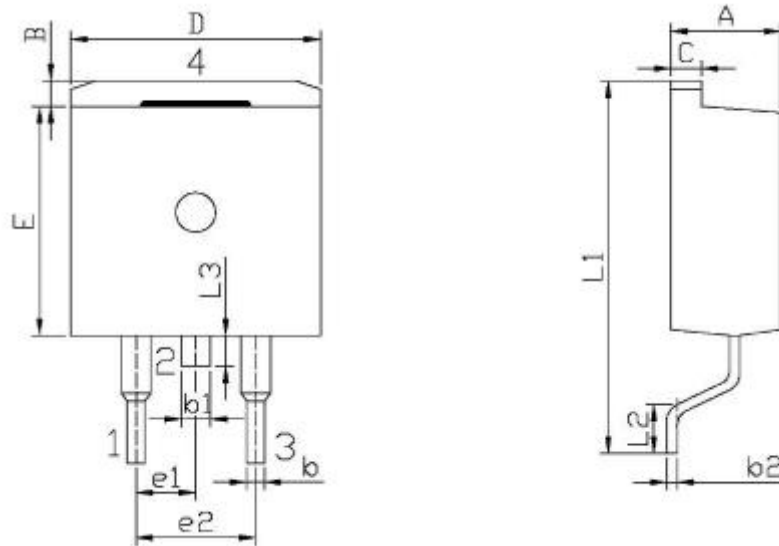
Figure 11: Normalized Breakdown Voltage vs Junction Temperature

Figure 12: Normalized On Resistance vs Junction Temperature

Figure 13: Drain-to-Source On Resistance vs Gate Voltage and Drain Current

Figure 14: Maximum Safe Operation Area


Figure 13: Maximum Effective Transient Thermal Impedance, Junction-to-Case


Mechanical Dimensions (TO-263 Unit: mm)


Symbol	Dimensions(mm)		
	Min.	Typ.	Max.
A	4.3	-	4.7
B	1.0	-	1.4
b	0.7	-	0.9
b1	1.15	-	1.35
C	1.20	-	1.40
D	9.8	-	10.20
E	9.0	-	9.4
e1	2.34	-	2.74
e2	4.88	-	5.28
L1	15.0	-	16.0
L2	2.24	-	2.84
L3	1.2	-	1.60

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